

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination ABBOTT ET AL.	
		Examiner	Art Unit	Page 1 of 3
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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		Examiner Scott L. Jarrett	Art Unit 3623	Page 2 of 3

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		Examiner	Art Unit	Page 3 of 3

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